

AMENDMENTS TO THE CLAIMS:

The following listing of claims replaces all prior listings, and all prior versions, of claims in the application.

Listing Of Claims:

1. (Previously presented) An IC card apparatus comprising:
 - at least one gate electrode,
 - a gate insulating film,
 - at least one source electrode,
 - at least one drain electrode, and
 - a semiconductor layer,
 - on a substrate, and
 - wherein said semiconductor layer is located so as to contact said gate insulating film only at regions which act as channel regions of the IC card apparatus,
 - wherein a patterned insulating layer is located between the gate insulating film and the semiconductor layer at positions other than at said channel regions, and
 - wherein said patterned insulating layer is a photosensitive insulating film.
2. (Previously presented) An IC card apparatus as claimed in claim 1, wherein said semiconductor layer is an organic semiconductor layer.
3. (Cancelled)

4. (Previously presented) An IC card apparatus as claimed in claim 1, wherein said substrate is a plastic substrate.

5. (Previously presented) An IC card apparatus as claimed in claim 4, wherein said plastic substrate is made of polymer material.

6. (Previously presented) An IC card apparatus as claimed in claim 1, wherein each channel region has a size which is a same size as a gate electrode, of the at least one gate electrode.

7. (Cancelled)

8. (Currently amended) An IC card apparatus as claimed in claim 11, wherein the channel regions, in plan view, are between respective source and drain electrodes, of the at least one source electrode and the at least one drain electrode, wherein the respective source and drain electrodes contact opposite ends of the semiconductor layer contacting the gate insulating film, and wherein the at least one gate electrode is above or beneath the semiconductor layer contacting the gate insulating film.

9. (Previously presented) An IC card apparatus as claimed in claim 8, wherein each channel region has a size which is a same size as a gate electrode, of the at least one gate electrode.

10. (Previously presented) An IC card apparatus as claimed in claim 8, wherein said semiconductor layer is an organic semiconductor layer.

11. (Previously presented) An IC card apparatus comprising:
at least one gate electrode,
a gate insulating film,
at least one source electrode,
at least one drain electrode, and
a semiconductor layer,
on a substrate, and
wherein said semiconductor layer is located so as to contact said gate insulating film only at regions which act as channel regions of the IC card apparatus, wherein a patterned insulating layer is located between the gate insulating film and the semiconductor layer at positions other than at said channel regions, and wherein material of the gate insulating film is different from material of the patterned insulating layer.